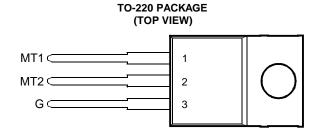


- 8 A RMS, 70 A Peak
- Glass Passivated Wafer
- 400 V to 800 V Off-State Voltage
- Max I_{GT} of 50 mA (Quadrants 1 3)



Pin 2 is in electrical contact with the mounting base.

absolute maximum ratings over operating case temperature (unless otherwise noted)

RATING			VALUE	UNIT
	TR8-400-70		400	
Repetitive peak off-state voltage (see Note 1)	TR8-600-70	V	600	V
	TR8-700-70	V_{DRM}	700	V
	TR8-800-70		800	
Full-cycle RMS on-state current at (or below) 85°C case temperature (see Note 2)			8	Α
Peak on-state surge current full-sine-wave (see Note 3)			70	Α
Peak on-state surge current half-sine-wave (see Note 4)			80	Α
Peak gate current			±1	Α
Peak gate power dissipation at (or below) 85°C case temperature (pulse width ≤ 200 μs)			2.2	W
Average gate power dissipation at (or below) 85°C case temperature (see Note 5)			0.9	W
Operating case temperature range			-40 to +110	°C
Storage temperature range			-40 to +125	°C
Lead temperature 1.6 mm from case for 10 seconds			230	°C

- NOTES: 1. These values apply bidirectionally for any value of resistance between the gate and Main Terminal 1.
 - 2. This value applies for 50-Hz full-sine-wave operation with resistive load. Above 85°C derate linearly to 110°C case temperature at the rate of 320 mA/°C.
 - 3. This value applies for one 50-Hz full-sine-wave when the device is operating at (or below) the rated value of on-state current. Surge may be repeated after the device has returned to original thermal equilibrium. During the surge, gate control may be lost.
 - 4. This value applies for one 50-Hz half-sine-wave when the device is operating at (or below) the rated value of on-state current. Surge may be repeated after the device has returned to original thermal equilibrium. During the surge, gate control may be lost.
 - 5. This value applies for a maximum averaging time of 20 ms.

electrical characteristics at 25°C case temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS			MIN	TYP	MAX	UNIT
I _{DRM}	Repetitive peak off-state current	V _D = rated V _{DRM}	I _G = 0	T _C = 110°C			±2	mA
		V _{supply} = +12 V†	$R_L = 10 \Omega$	t _{p(g)} > 20 μs		2	50	
I _{GTM}	Peak gate trigger	$V_{\text{supply}} = +12 \text{ V}\dagger$	$R_L = 10 \Omega$	$t_{p(g)} > 20 \mu s$		-12	-50	mA
	current	$V_{\text{supply}} = -12 \text{ V}^{\dagger}$	$R_L = 10 \Omega$	$t_{p(g)} > 20 \mu s$		-9	-50	
		$V_{\text{supply}} = -12 \text{ V}\dagger$	$R_L = 10 \Omega$	t _{p(g)} > 20 μs		20		
V _{GTM}		V _{supply} = +12 V†	$R_L = 10 \Omega$	t _{p(g)} > 20 μs		0.7	2	
	Peak gate trigger	$V_{\text{supply}} = +12 \text{ V}\dagger$	$R_L = 10 \Omega$	$t_{p(g)} > 20 \mu s$		-0.8	-2	V
	voltage	$V_{\text{supply}} = -12 \text{ V}^{\dagger}$	$R_L = 10 \Omega$	t _{p(g)} > 20 μs		-0.8	-2	
		V _{supply} = -12 V†	$R_L = 10 \Omega$	t _{p(g)} > 20 μs		0.9	2	

[†] All voltages are with respect to Main Terminal 1.

electrical characteristics at 25°C case temperature (unless otherwise noted) (continued)

PARAMETER TEST CONDITIONS			MIN	TYP	MAX	UNIT		
V_{TM}	Peak on-state voltage	I _{TM} = ±12 A	$I_G = 50 \text{ mA}$	(see Note 6)		±1.6	±2.1	V
1	Holding current	V _{supply} = +12 V†	I _G = 0	Init' I _{TM} = 100 mA		5	30	mA
I _H		$V_{\text{supply}} = -12 \text{ V}\dagger$	$I_G = 0$	Init' $I_{TM} = -100 \text{ mA}$		-9	-30	
I.	Latching current	V _{supply} = +12 V†	(see Note 7)			50	mA	
\		$V{\text{supply}} = -12 \text{ V}\dagger$					-50	IIIA
dv/dt	Critical rate of rise of	V _{DRM} = Rated V _{DRM}	I _G = 0	T _C = 110°C		±100		V/µs
uv/ut	off-state voltage			1C = 110 C		±100		V/μ5
dv/dt _(c)	Critical rise of commu-	V _{DRM} = Rated V _{DRM}	I _{TRM} = ±12 A	T _C = 85°C	±5			V/µs
	tation voltage			1C = 02 C	±0			v/μS

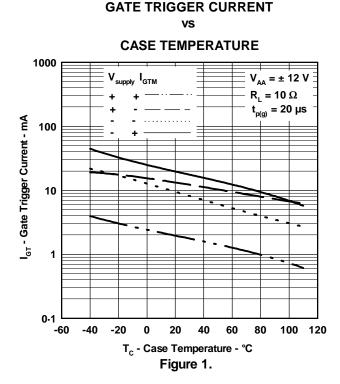
[†] All voltages are with respect to Main Terminal 1.

- NOTES: 6. This parameter must be measured using pulse techniques, $t_p = \le 1$ ms, duty cycle ≤ 2 %. Voltage-sensing contacts separate from the current carrying contacts are located within 3.2 mm from the device body.
 - 7. The triacs are triggered by a 15-V (open-circuit amplitude) pulse supplied by a generator with the following characteristics: $R_G = 100 \ \Omega$, $t_{p(q)} = 20 \ \mu s$, $t_r = \le 15 \ ns$, $f = 1 \ kHz$.

thermal characteristics

PARAMETER			MAX	UNIT
R _{0JC} Junction to case thermal resistance			1.8	°C/W
R _{0JA} Junction to free air thermal resistance			62.5	°C/W

TYPICAL CHARACTERISTICS



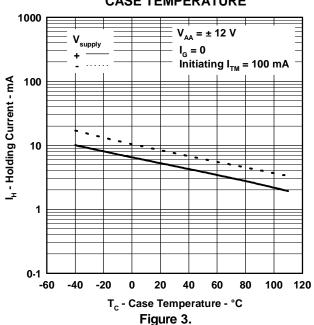
٧S **CASE TEMPERATURE** 10 $V_{AA} = \pm 12 V$ $V_{\text{supply}} I_{\text{GTM}}$ $R_L = 10 \Omega$ $t_{p(g)} = 20 \mu s$ V_{GT} - Gate Trigger Voltage - V -60 -40 -20 0 20 40 60 80 100 120 T_c - Case Temperature - °C Figure 2.

GATE TRIGGER VOLTAGE

TYPICAL CHARACTERISTICS

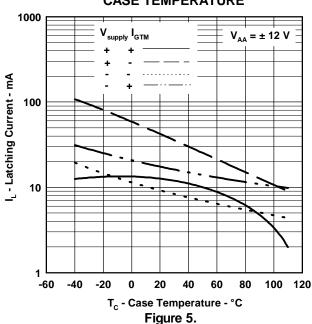
HOLDING CURRENT vs

CASE TEMPERATURE

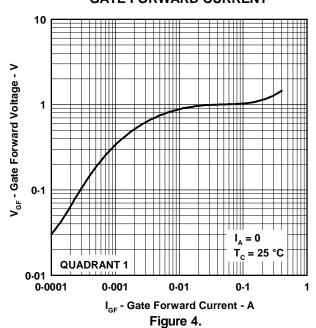


LATCHING CURRENT vs

CASE TEMPERATURE

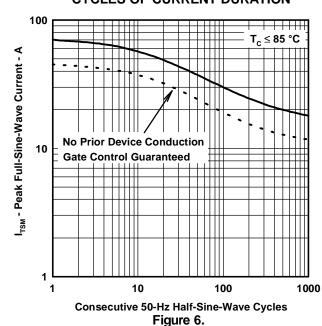


GATE FORWARD VOLTAGE vs GATE FORWARD CURRENT

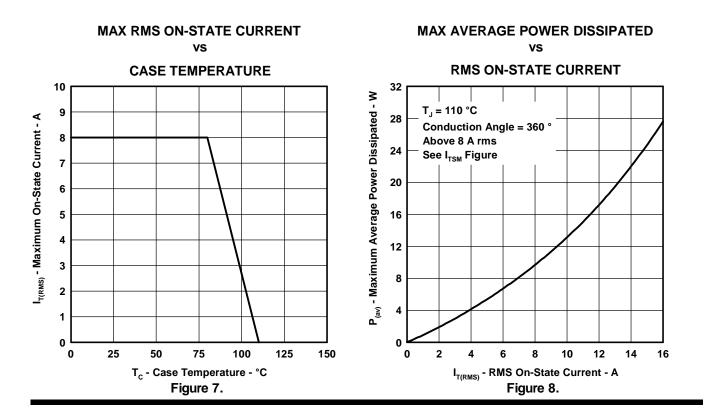


SURGE ON-STATE CURRENT vs

CYCLES OF CURRENT DURATION



TYPICAL CHARACTERISTICS



PARAMETER MEASUREMENT INFORMATION V_{AC} V_{AC} I_{TRM} V_{DRM} V_{DRM} V_{MT2} V_{MT2}

NOTE A: The gate-current pulse is furnished by a trigger circuit which presents essentially an open circuit between pulses. The pulse is timed so that the off-state-voltage duration is approximately 800 µs.

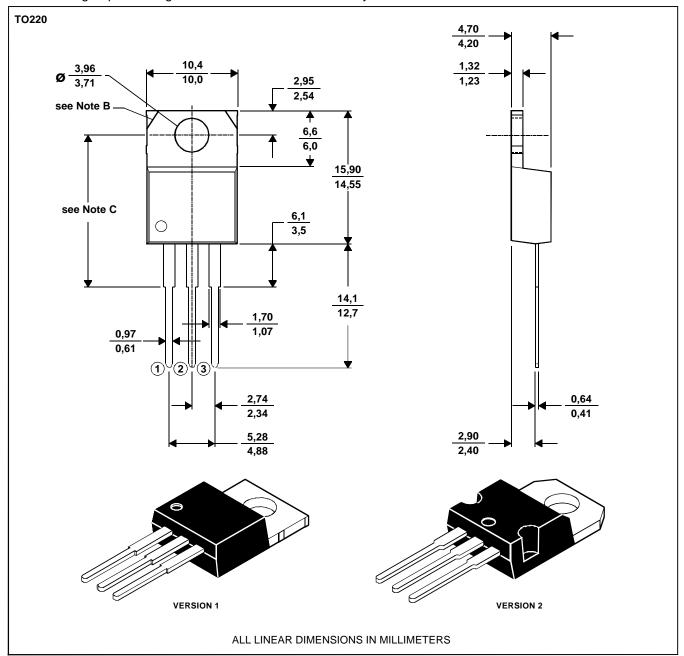
Figure 9.

MECHANICAL DATA

TO-220

3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



NOTES: A. The centre pin is in electrical contact with the mounting tab.

- B. Mounting tab corner profile according to package version.
- C. Typical fixing hole centre stand off height according to package version. Version 1, 18.0 mm. Version 2, 17.6 mm.